

**Notice of References Cited**

Application/Control No.

10/576,795

Applicant(s)/Patent Under  
Reexamination  
SHIFF ET AL.

Examiner

TUAN A. PHAM

Art Unit

2618

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,054,301	05-2006	Sousa et al.	370/343
	B	US-			
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	L	US-			
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